TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HCT7007AP,TC74HCT7007AF

Hex Buffer

The TC74HCT7007A is a high speed CMOS BUFFER fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

The internal circuit is composed of 4 stages including a buffer output, which provides high noise immunity and stable output.

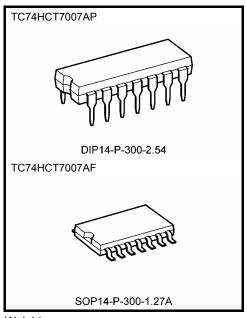
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $t_{pd} = 11 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 1 \mu A \text{ (max)}$ at $T_{a} = 25 \text{°C}$
- Compatible with TTL outputs: $V_{IH} = 2 V (min)$

 $V_{\rm IL} = 0.8 \text{ V (max)}$

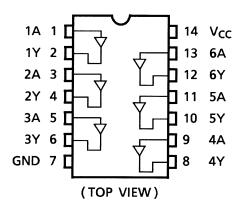
- Wide interfacing ability: LSTTL, NMOS, CMOS
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: | I_{OH} | = I_{OL} = 4 mA (min)
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Pin and function compatible with 74LS07



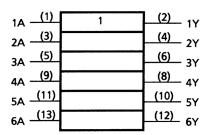
Weight

DIP14-P-300-2.54 : 0.96 g (typ.) SOP14-P-300-1.27A : 0.18 g (typ.)

Pin Assignment



IEC Logic Symbol



2007-10-01

Truth Table

Α	Υ
L	L
Н	Н

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7	V
DC input voltage	V _{IN}	-0.5~V _{CC} + 0.5	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	I _{IK}	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $Ta = -40^{\circ}C \sim 65^{\circ}C$. From $Ta = 65^{\circ}C$ to $85^{\circ}C$ a derating factor of -10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	4.5~5.5	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	t _r , t _f	0~500	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

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Electrical Characteristics

DC Characteristics

Characteristics Symbol		Test Condition $\begin{array}{c} V_{CC} \\ (V) \end{array}$		Ta = 25°C			Ta = -40~85°C			
					Min	Тур.	Max	Min	Max	Unit
High-level input voltage	V _{IH}		_		2.0	_	_	2.0		V
Low-level input voltage	V _{IL}	_		4.5~ 5.5	_	_	0.8	_	0.8	V
High-level output	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 μA	4.5	4.4	4.5		4.4	_	٧
voltage			I _{OH} = -4 mA	4.5	4.18	4.31		4.13		
Low-level output voltage	M	V _{IN}	I _{OL} = 20 μA	4.5	_	0.0	0.1	_	0.1	V
	VOL	= V _{IH} or V _{IL}	I _{OL} = 4 mA	4.5	_	0.17	0.26	_	0.33	V
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		5.5	_	_	±0.1	_	±1.0	μА
	Icc	$I_{CC} \qquad V_{IN} = V_{CC} \text{ or GND}$ $Per \text{ input: } V_{IN} = 0.5 \text{ V or } 2.4 \text{ V}$ $Other \text{ input: } V_{CC} \text{ or GND}$		5.5	_	_	1.0	_	10.0	μΑ
Quiescent supply current	Ic			5.5	_	_	2.0	_	2.9	mA

AC Characteristics ($C_L = 15 \text{ pF}$, $V_{CC} = 5 \text{ V}$, $Ta = 25^{\circ}\text{C}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t _{TLH}	_		6	12	ns
	t _{THL}					
Propagation delay time	t _{pLH}	_	_	11	17	ns
	t _{pHL}					

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

		Test Condition		Ta = 25°C			Ta = -40~85°C		
Characteristics	Symbol		V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
Output transition time	t _{TLH}	_	4.5	_	8	15	_	19	ns
	t _{THL}		5.5	_	7	14	_	18	
Propagation delay time	t _{pLH}	_	4.5	_	14	23	_	28	20
	t_{pHL}		5.5	_	12	21	_	26	ns
Input capacitance	C _{IN}	_		_	5	10	_	10	pF
Power dissipation capacitance	C _{PD} (Note)			_	22		_	_	pF

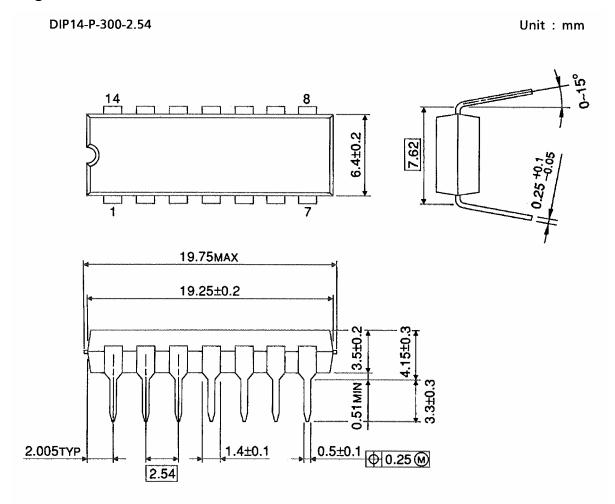
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/6$ (per gate)



Package Dimensions

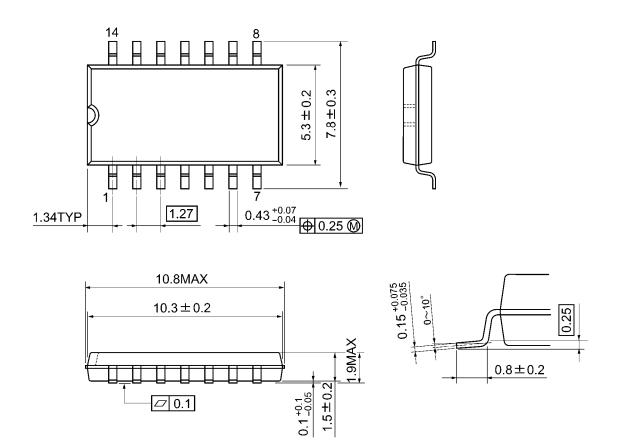


Weight: 0.96 g (typ.)

TOSHIBA

Package Dimensions

SOP14-P-300-1.27A Unit: mm



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Weight: 0.18 g (typ.)

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